

Volume 16, Number 4

August 2010

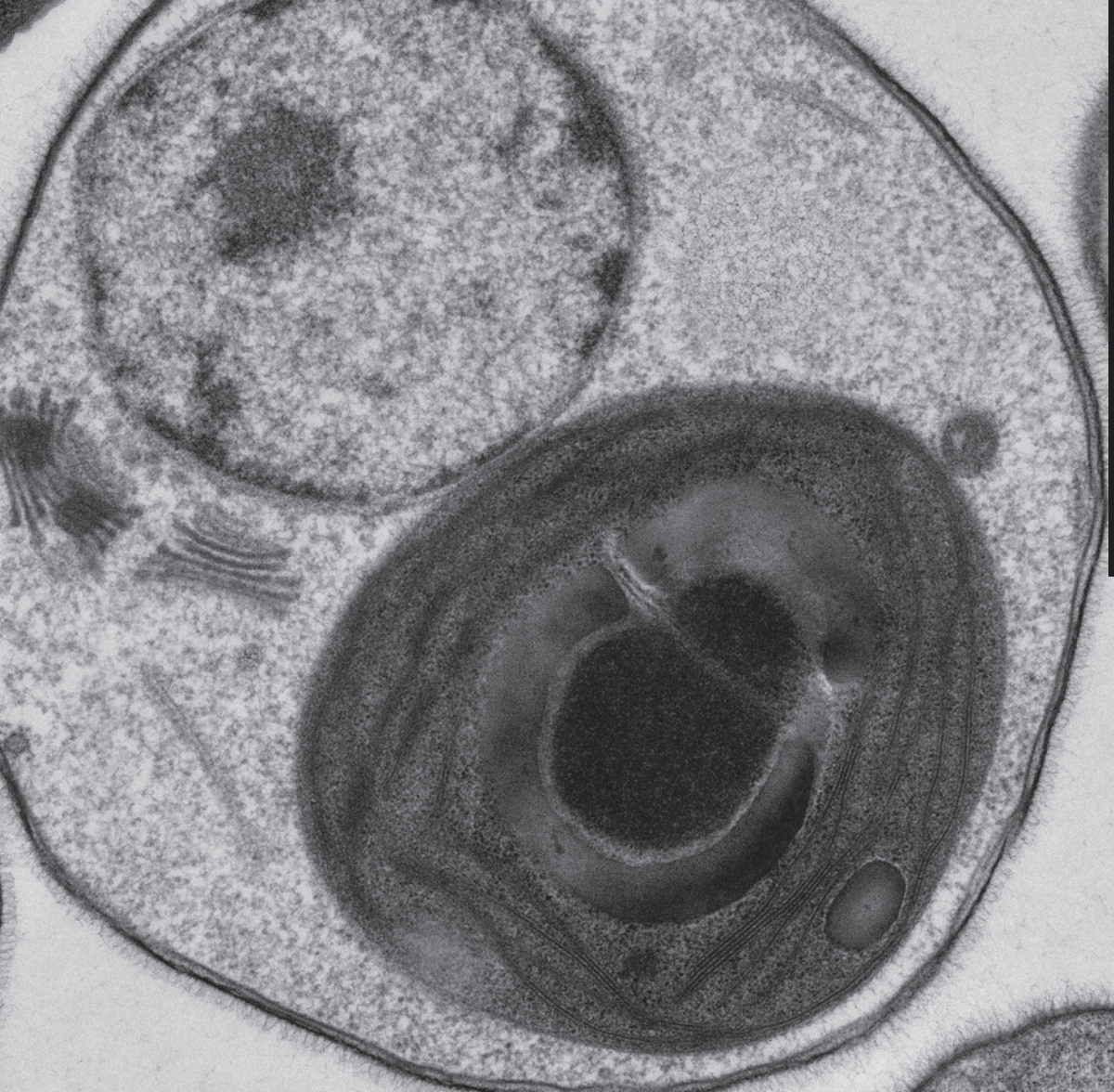
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## SPECIAL SECTION—ABERRATION-CORRECTED ELECTRON MICROSCOPY

Introduction—The Otto Scherzer Special Issue on Aberration-Corrected Electron Microscopy 365

*David J. Smith and Uli Dahmen*

The Contributions of Otto Scherzer (1909–1982) to the Development of the Electron Microscope 366

*Michael Marko and Harald Rose*

Behavior of Au Species in Au/Fe<sub>2</sub>O<sub>3</sub> Catalysts Characterized by Novel *In Situ* Heating Techniques and Aberration-Corrected STEM Imaging 375

*Lawrence F. Allard, Maria Flytzani-Stephanopoulos, and Steven H. Overbury*

Sub-Ångstrom Low Voltage Performance of a Monochromated, Aberration-Corrected Transmission Electron Microscope 386

*David C. Bell, Christopher J. Russo, and Gerd Benner*

Information Transfer in a TEM Corrected for Spherical and Chromatic Aberration 393

*M. Haider, P. Hartel, H. Müller, S. Uhlemann, and J. Zach*

Exceeding Conventional Resolution Limits in High-Resolution Transmission Electron Microscopy Using Tilted Illumination and Exit-Wave Restoration 409

*Sarah J. Haigh, Hidetaka Sawada, Kunio Takayanagi, and Angus I. Kirkland*

Imaging, Core-Loss, and Low-Loss Electron-Energy-Loss Spectroscopy Mapping in Aberration-Corrected STEM 416

*Sorin Lazar, Yang Shao, Lina Gunawan, Riad Nechache, Alain Pignolet, Gianluigi A. Botton*

Surface Channeling in Aberration-Corrected Scanning Transmission Electron Microscopy of Nanostructures 425

*Jingyue Liu and Lawrence F. Allard*

Aberration Correction and Electron Holography 434

*Hannes Lichte, Martin Linck, Dorin Geiger, and Michael Lehmann*

Zernike Phase Contrast Electron Microscopy with a Spherically Corrected Foil Lens 441

*Dieter Typke*

Three-Dimensional Imaging in Aberration-Corrected Electron Microscopes 445

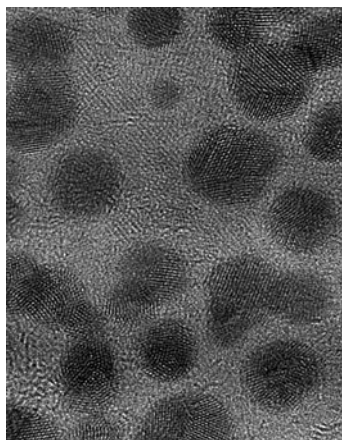
*Huolin L. Xin and David A. Muller*

## BIOLOGICAL APPLICATIONS

Transmission Electron Microscopy of Lipid Vesicles for Drug Delivery: Comparison between Positive and Negative Staining 456

*Valentina Bello, Giovanni Mattei, Paolo Mazzoldi, Nicoletta Vivenza, Paolo Gasco, Jean Marc Idee, Caroline Robic, and Elisabetta Borsella*

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**On the Cover:** Gold nanoparticle islands on multilayer graphene film imaged with electron monochromation. For further information see Bell et al. on page 386.



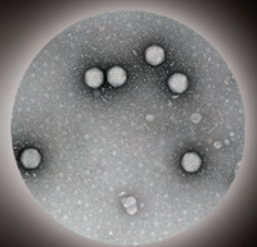
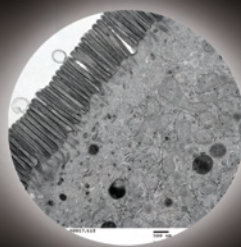
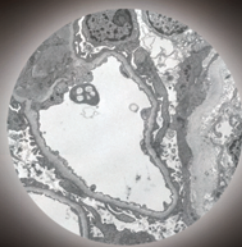
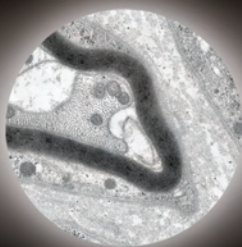
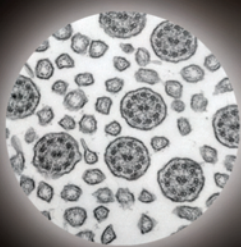
Novel Electron Tomographic Methods to Study the Morphology of Keratin Filament Networks <i>Michaela Sailer, Katharina Höhn, Sebastian Lück, Volker Schmidt, Michael Beil, and Paul Walther</i>	462
Morphological Fractal Analysis of Shape in Cancer Cells Treated with Combinations of Microtubule-Polymerizing and -Depolymerizing Agents <i>Sonal O. Uppal, Dmitri V. Voronine, Elizabeth Wendt, and Carol A. Heckman</i>	472
Accurate Detection of Low Levels of Fluorescence Emission in Autofluorescent Background: <i>Franciscella</i> -Infected Macrophage Cells <i>Ryan W. Davis, Jerilyn A. Timlin, Julia N. Kaiser, Michael B. Sinclair, Howland D.T. Jones, and Todd W. Lane</i>	478
Study of the Changes in Insoluble Polysaccharides during Pollen Development in Rice ( <i>Oryza sativa</i> L.) by Microscopic Multispectral Imaging <i>Shunan Liu, Lei Pan, Qiongshui Wu, Yaojun Hu, Xiaojun Chen, and Yi Ding</i>	488
<b>BOOK REVIEW</b>	
<i>Ultrastructural Pathology: The Comparative Cellular Basis of Disease</i> , 2nd edition. Norman F. Cheville <i>Susan A. Elmore</i>	502
<b>CALENDAR OF MEETINGS AND COURSES</b>	503





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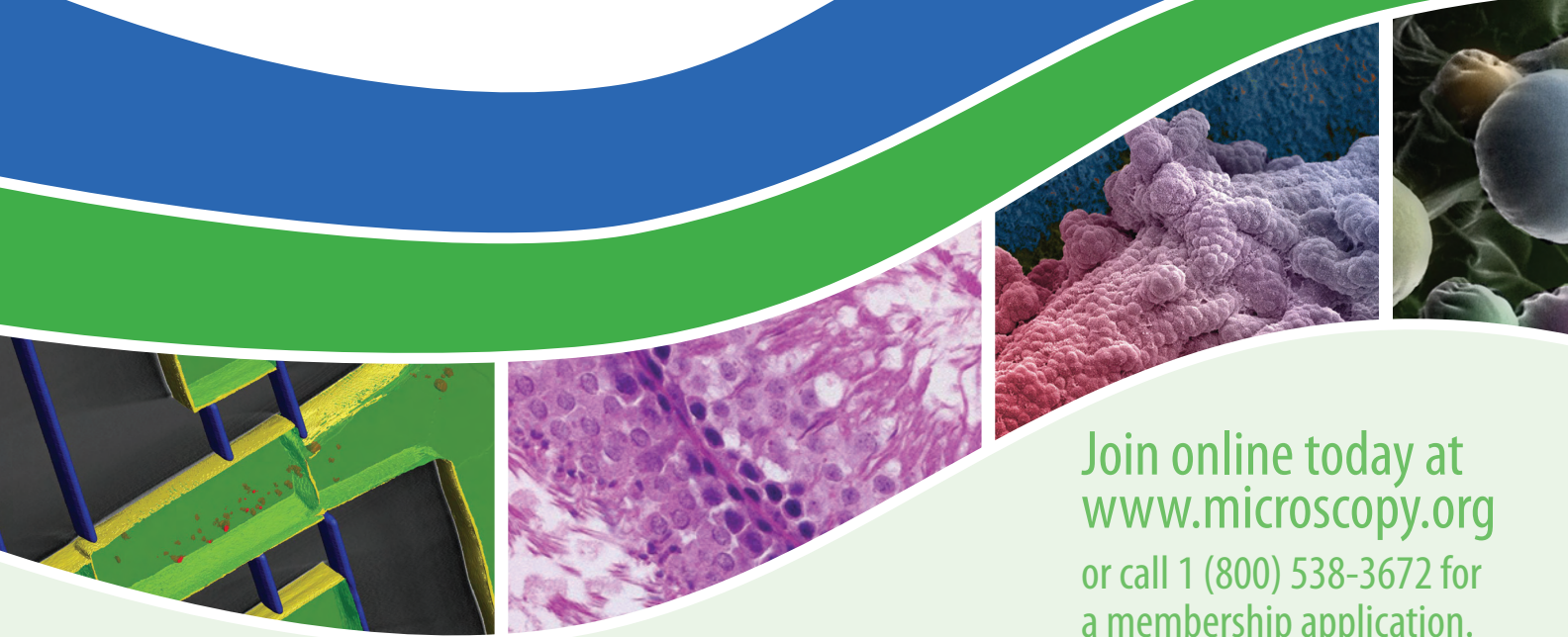
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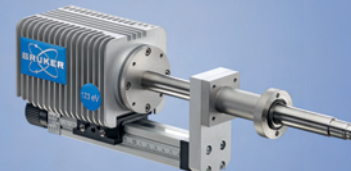
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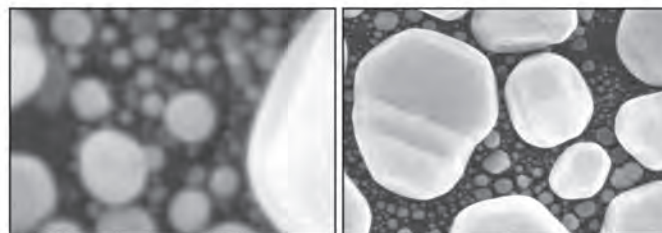
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**Loaded system:** Includes Schottky FESEM with Gemini column, specimen interlock, EDAX Apollo 40 SDD EDS, TSL EBSD, Denton Desk IV TSC turbo fine grain sputter coater, Robinson 8.2 scintillator motorized BSE with joystick control unit, STEM, VPSE detector, CL in high vacuum mode, Haskris R050 chiller, two Liebert Nfinity double conversion UPS units with Ethernet connectivity, Deben XP hot/cold stage. All pumping systems are dry. Latest SmartSEM Zeiss GUI. WindowsXP/Pro SP3 with XP Office Pro. Triple LCD monitors with Zeiss hardpanel with keyboard and mouse to control SEM, EDS and EBSD.

Details can be found here:

**System items:**

<http://www.microtechnics.com/supra55vp/suprasummary3v2.pdf>

**Pictures:**

<http://www.microtechnics.com/supra55vp/Page.html>

Please inquire with any questions. Asking \$375,000. System has been on maintenance contract since purchase in July 2004, acceptance Jan 2005. Not a refurbished unit. Up and running and can be demonstrated. New tip and alignment. Packing, shipping and insurance and re-install at buyer's cost. Price is negotiable. 916-791-8191 [gary@microtechnics.com](mailto:gary@microtechnics.com)



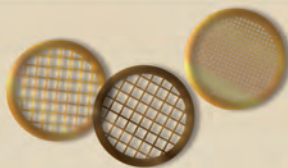
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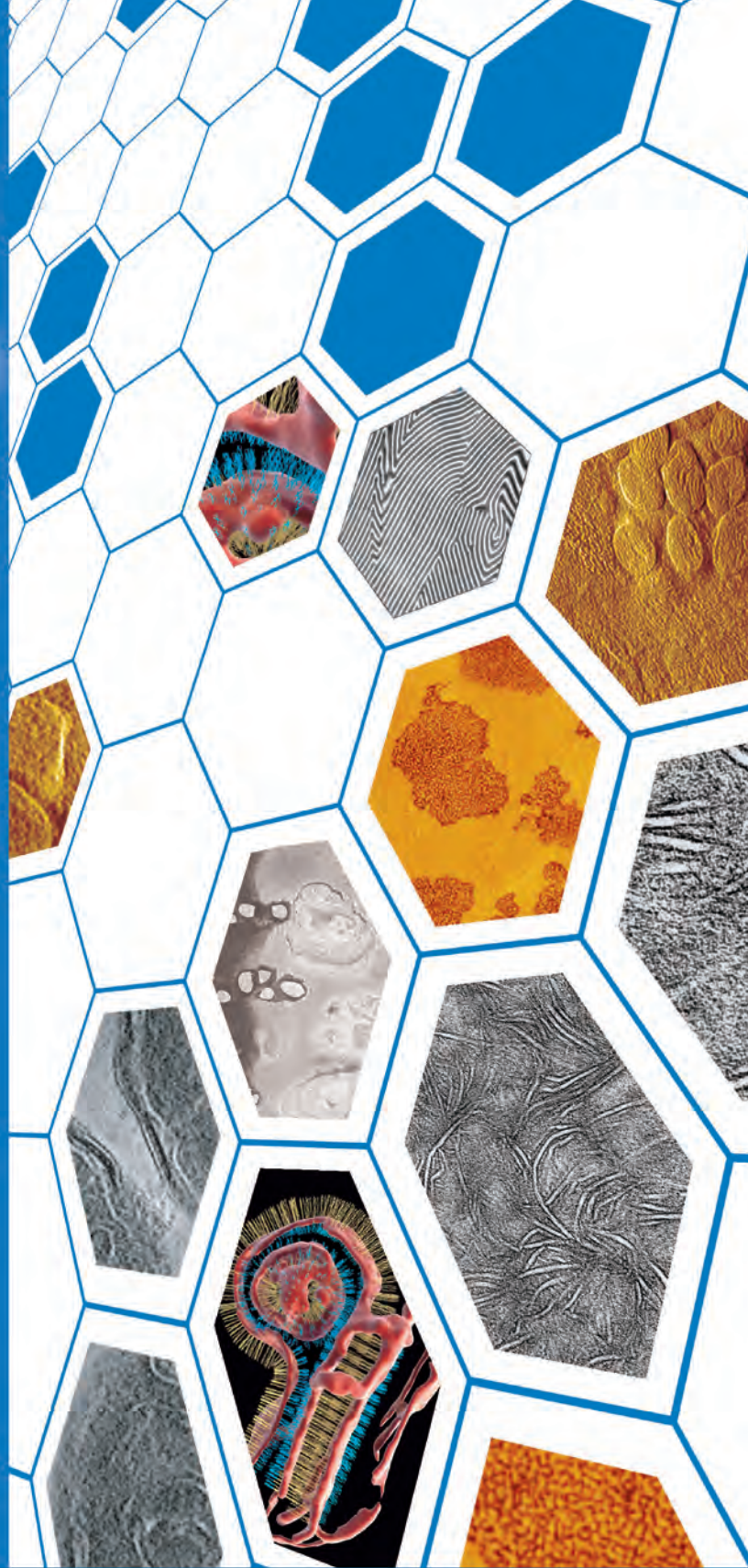
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